

## REFERENCES

## 5.3 (cont.)

- Windisch, D. & Becker, P. (1990). *Silicon lattice parameters as an absolute scale of length for high precision measurements of fundamental constants*. *Phys. Status Solidi A*, **118**, 379–388.
- Wołczyrz, M. & Łukaszewicz, K. (1982). *The evaluation of crystal perfection by means of the asymmetric Bragg reflections*. *J. Appl. Cryst.* **15**, 406–411.
- Wołczyrz, M., Pietraszko, A. & Łukaszewicz, K. (1980). *The application of asymmetric Bragg reflections in the Bond method of measuring lattice parameters*. *J. Appl. Cryst.* **13**, 12–16.
- Wölfel, E. R. (1971). *A new film instrument for the exploration of reciprocal space*. *J. Appl. Cryst.* **4**, 297–302.
- Woolfson, M. M. (1970). *An introduction to X-ray crystallography*. Cambridge University Press.
- Yakowitz, H. (1966a). *Effect of sample thickness and operating voltage on the contrast of Kossel transmission photographs*. *J. Appl. Phys.* **37**, 4455–4458.
- Yakowitz, H. (1966b). *Precision of cubic lattice parameter measurement by the Kossel technique*. *The electron microprobe*, edited by T. D. McKinley, K. F. J. Heinrich & D. B. Wittry, pp. 417–438. New York: John Wiley.
- Yakowitz, H. (1969). *The divergent beam X-ray technique*. *Advances in electronics and electron physics*, edited by A. J. Tousimis & L. Marton, Suppl. 6, pp. 361–431. New York: Academic Press.
- Yakowitz, H. (1972). *Use of divergent-beam X-ray diffraction to measure lattice expansion in LiF as a function of thermal-neutron dose up to  $6 \times 10^{16}$  nvt*. *J. Appl. Phys.* **43**, 4793–4794.
- Zolotoyabko, E., Sander, B., Komem, Y. & Kantor, B. (1993). *Improved strain analysis in semiconductor crystals by X-ray diffractometry enhanced with ultrasound*. *Appl. Phys. Lett.* **63**, 1540–1542.

## 5.4.1

- Edington, J. W. (1975). *Electron diffraction in the electron microscope*. *Monographs in practical electron microscopy in materials science*, No. 2. Eindhoven: N. V. Philips Gloeilampenfabrieken.
- Gard, J. A. (1976). *Electron microscopy in mineralogy*, p. 52. Berlin: Springer.
- Hirsch, P. B., Howie, A., Nicholson, R. B., Pashley, D. W. & Whelan, M. J. (1965). *Electron microscopy of thin crystals*. London: Butterworth.
- International Tables for Crystallography* (1983). Vol. A. Dordrecht: Kluwer Academic Publishers.
- LePage, Y. (1992). *Ab initio primitive cell parameters from single convergent beam patterns: a converse route to the identification of microcrystals with electrons*. *Miscrosc. Res. Tech.* **21**, 158–165.

- Zuo, J. M. (1993). *New method of Bravais lattice determination*. *Ultramicroscopy*, **52**, 459–464.

## 5.4.2

- FitzGerald, J. D. & Johnson, A. W. S. (1984). *A simplified method of electron microscope voltage measurement*. *Ultramicroscopy*, **12**, 231–236.
- Gjønnnes, J. & Olsen, A. (1984). *Analytical electron microscopy*. *JEOL News*, **22E**, 13–18.
- Høier, R. (1969). *A method to determine the ratio between lattice parameter and electron wavelength from Kikuchi line intersections*. *Acta Cryst.* **A25**, 516–518.
- Jones, P. M., Rackham, G. M. & Steeds, J. W. (1977). *Higher order Laue zone effects in electron diffraction and their use in lattice parameter determination*. *Proc. R. Soc. London Ser. A*, **354**, 197–222.
- Olsen, A. (1976a). *Lattice parameter determination using Kikuchi-line intersections: application to olivine and feldspar*. *J. Appl. Cryst.* **9**, 9–13.
- Olsen, A. (1976b). *Determination of lattice constants using Kikuchi line intersections*. Solid State Group Report Series. Institute of Physics, University of Oslo, Norway.
- Rackham, G. M., Jones, P. M. & Steeds, J. W. (1974). *Upper layer diffraction effects in zone axis patterns*. Proceedings of the Eighth International Congress on Electron Microscopy, Canberra, Australia, pp. 336–337.
- Steeds, J. W. (1979). *Convergent beam electron diffraction*. *Introduction to analytical electron microscopy*, edited by J. J. Hren, J. I. Goldstein & D. C. Joy, pp. 387–422. New York: Plenum.
- Thomas, G. (1970). *Kikuchi electron diffraction and applications*. *Modern diffraction and imaging techniques in material science*, edited by S. Amelinckx, S. Gevers, G. Remaut & J. Van Landuyt, pp. 131–185. Amsterdam: North-Holland.
- Uyeda, R., Nonoyama, M. & Kogiso, M. (1965). *Determination of the wavelength of electrons from a Kikuchi pattern*. *J. Electron Microsc.* **14**, 296–300.
- Walker, A. R. & Booker, G. R. (1982). *A selected-area channelling pattern (SACP) method for measuring small local changes in lattice parameter with bulk specimens*. *Electron microscopy 1982*, Vol. 1, pp. 651–652. Hamburg: Elsevier.

## 5.5

- Fischer, P., Zolliker, P., Meier, B. H., Ernst, R. R., Hewat, A. W., Jorgensen, J. D. & Rotella, F. J. (1986). *Structure and dynamics of terephthalic acid from 2 to 300 K*. *J. Solid State Chem.* **61**, 109–125.